DESCRIPTION

Explores the uses of TXRF in micro- and trace analysis, and in surface- and near-surface-layer analysis

• Pinpoints new applications of TRXF in different fields of biology, biomonitoring, material and life sciences, medicine, toxicology, forensics, art history, and archaeometry

• Updated and detailed sections on sample preparation taking into account nano- and picoliter techniques

• Offers helpful tips on performing analyses, including sample preparations, and spectra recording and interpretation

• Includes some 700 references for further study

ABOUT THE AUTHOR

Reinhold Klockenkämper is physicist and was head of the Physical Analysis Research Group at ISAS in Dortmund, Germany. Furthermore, he was Associate Lecturer at the University of Applied Sciences in Dortmund. His experience in X-ray spectral analysis spans four decades and he published over 100 scientific papers and several book articles. He was member of three Editorial Advisory Boards of international journals for many years. In 1988 and 1996 he organized the 2nd and the 6th conference on TXRF in Dortmund. In 1996 he published the first edition of this monograph on TXRF. Professor Klockenkämper retired in 2002, but is currently working as guest scientist at ISAS.
Alex von Bohlen is engineer and senior scientist at the Leibniz-Institut für Analytische Wissenschaften –ISAS– e.V. in Dortmund. He is head of the X-ray laboratories and of the scanning electron and optical microscopy facilities. In addition, he is responsible for the beamline 2 at DELTA, Center for Synchrotron Radiation at the Technical University of Dortmund. Dr. von Bohlen has been working in the field of TXRF since more than 25 years, has published more than 120 articles, mostly dedicated to TXRF, and is member of two Editorial Advisory Boards. In 2011 he organized the 14th conference on TXRF in Dortmund.